

# Analyze and Optimize 32- to 56- Gbps Serial Link Channels

January 26, 2017



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Engineer Xilinx*



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# AGENDA

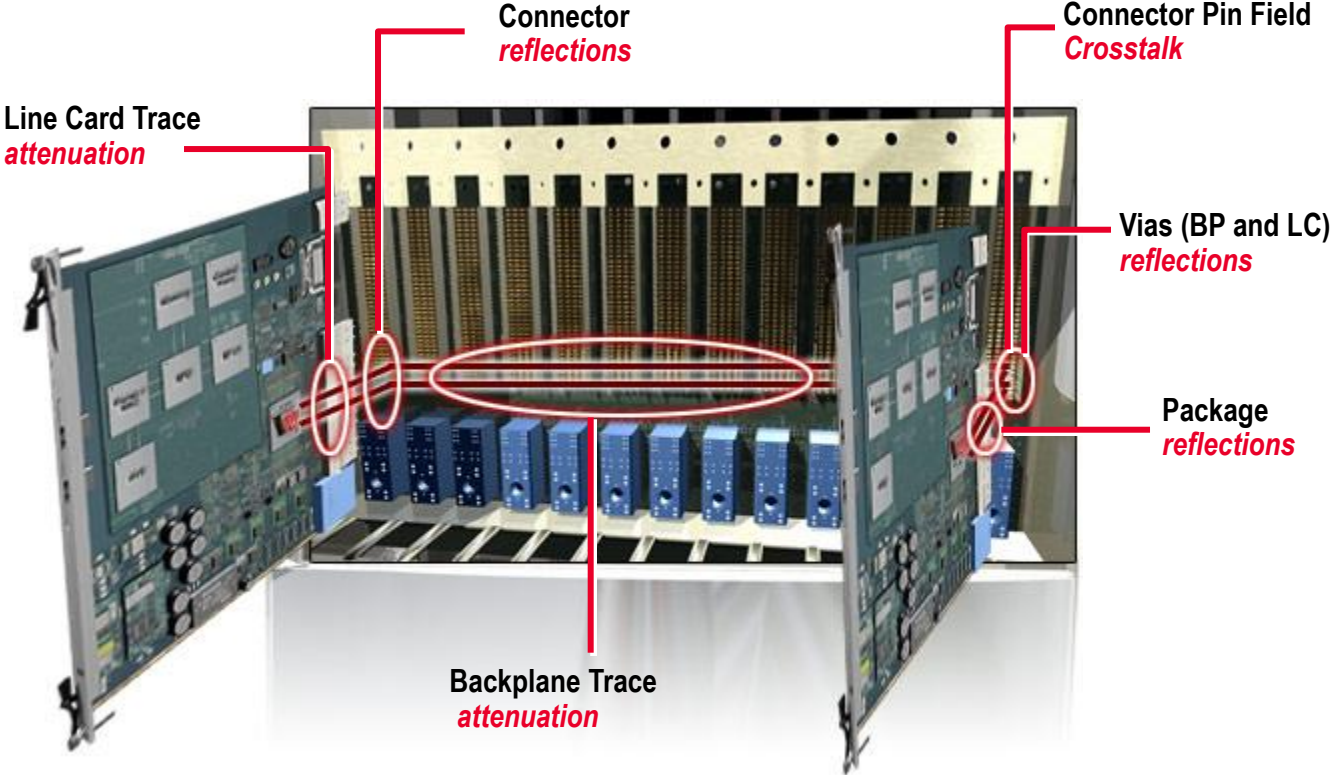


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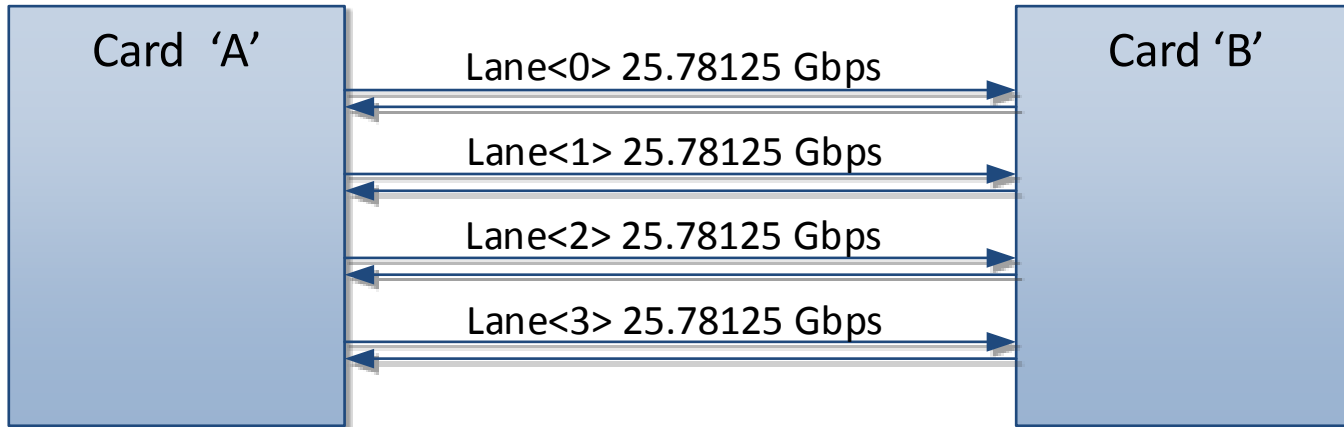
- ➔ • **Test Strategies for SerDes Channels**
- Forensic Channel Analysis
- Gaining Insight with the Pulse Response

# Serial I/O Channel – Backplane Channel



# 100GBASE-KR Backplane Interface

## 100GBASE-KR



# 100GBASE-KR Backplane Channel

IEEE Std 802.3-2015  
IEEE Standard for Ethernet  
SECTION SIX – Annex 93B

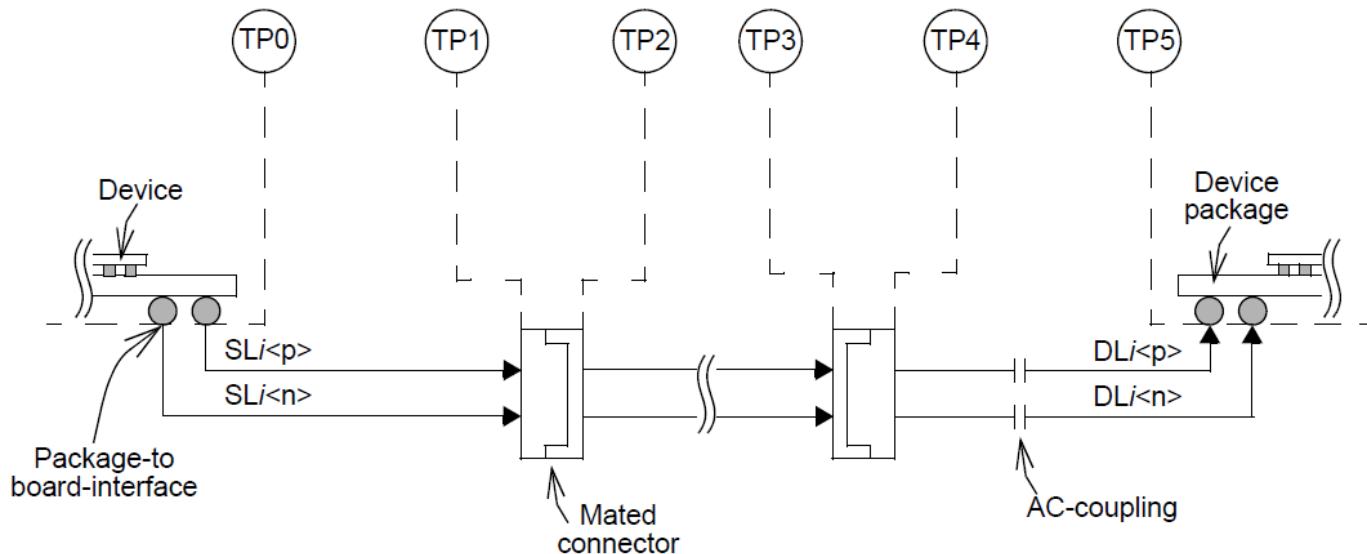


Figure 93B-1—Reference model (one direction from one lane is illustrated)

# 100GBASE-KR: Channel Testing

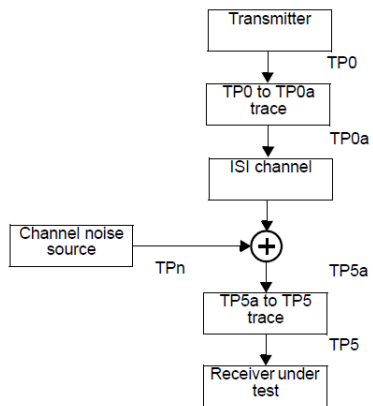


Figure 93C-2—Interference tolerance test setup

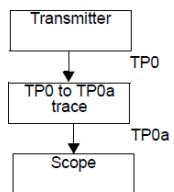


Figure 93C-3—Interference tolerance transmitter test setup

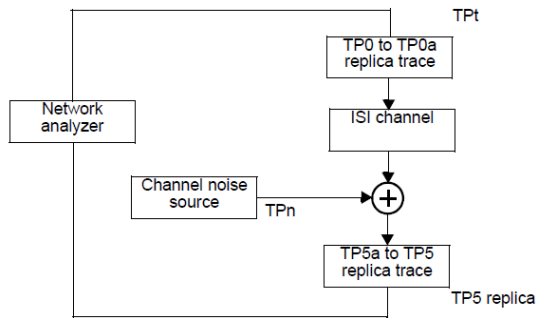
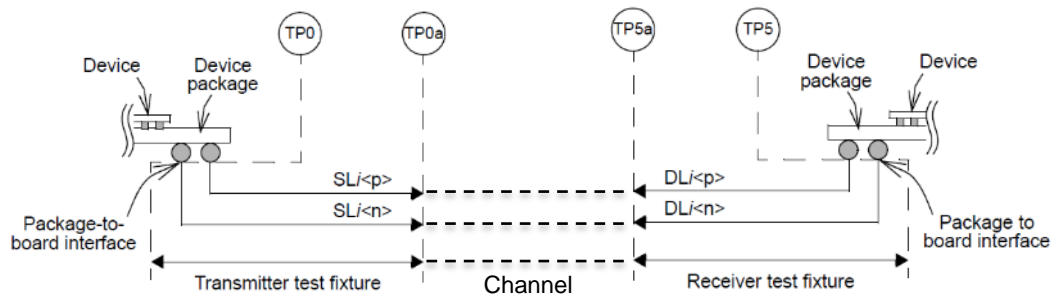


Figure 93C-4—Interference tolerance channel s-parameter test setup

IEEE Std 802.3-2015  
IEEE Standard for Ethernet  
SECTION SIX

# 100GBASE-KR: Channel Spec's

IEEE Std 802.3-2015  
IEEE Standard for Ethernet  
SECTION SIX

$$IL(f) \leq \left\{ \begin{array}{ll} 1.5 + 4.6\sqrt{f} + 1.318f & 0.05 \leq f \leq f_b/2 \\ -12.71 + 3.7f & f_b/2 < f \leq f_b \end{array} \right\} \text{ (dB)}$$

where

- $f$  is the frequency in GHz
- $f_b$  is the signaling rate (25.78125) in GHz
- $IL(f)$  is the insertion loss at frequency  $f$

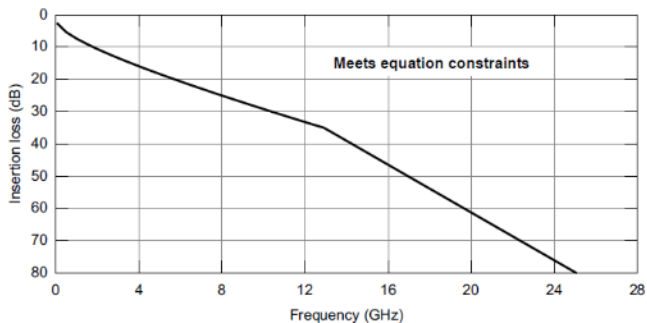


Figure 93-13—Insertion loss limit

$$RL_d(f) \geq \left\{ \begin{array}{ll} 12 & 0.05 \leq f \leq f_b/4 \\ 12 - 15\log_{10}(4f/f_b) & f_b/4 < f \leq f_b \end{array} \right\} \text{ dB}$$

where

- $f$  is the frequency in GHz
- $f_b$  is the signaling rate (25.78125) in GHz
- $RL(f)$  is the return loss at frequency  $f$

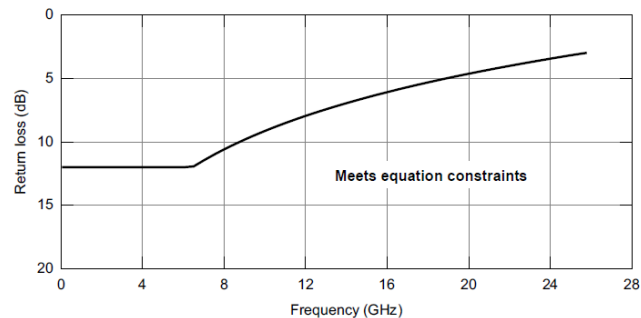
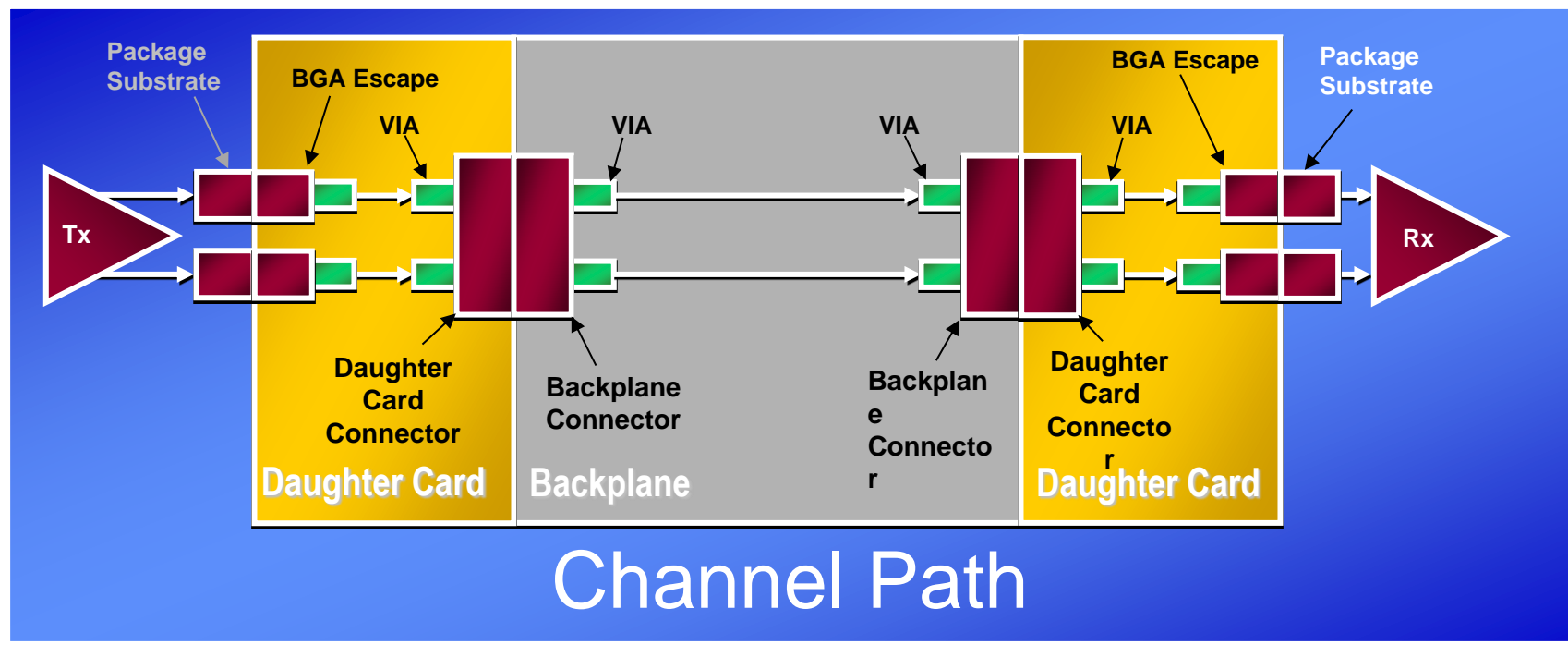


Figure 93-14—Differential return loss limit

# 100GBASE-KR: Channel Path Details – 1 Lane





# 100GBASE-KR: What's next?

- “No battle plan survives contact with the enemy”
  - Helmuth von Moltke
- “Everyone has a plan ‘til they get punched in the mouth”
  - Mike Tyson

**What if the link doesn't work?  
“Stay Tuned”**

# SerDes Link Debug – bits & pieces

## – Power Supplies

- MGTAVCC
- MGTAVTT
- MGTVCCAUX

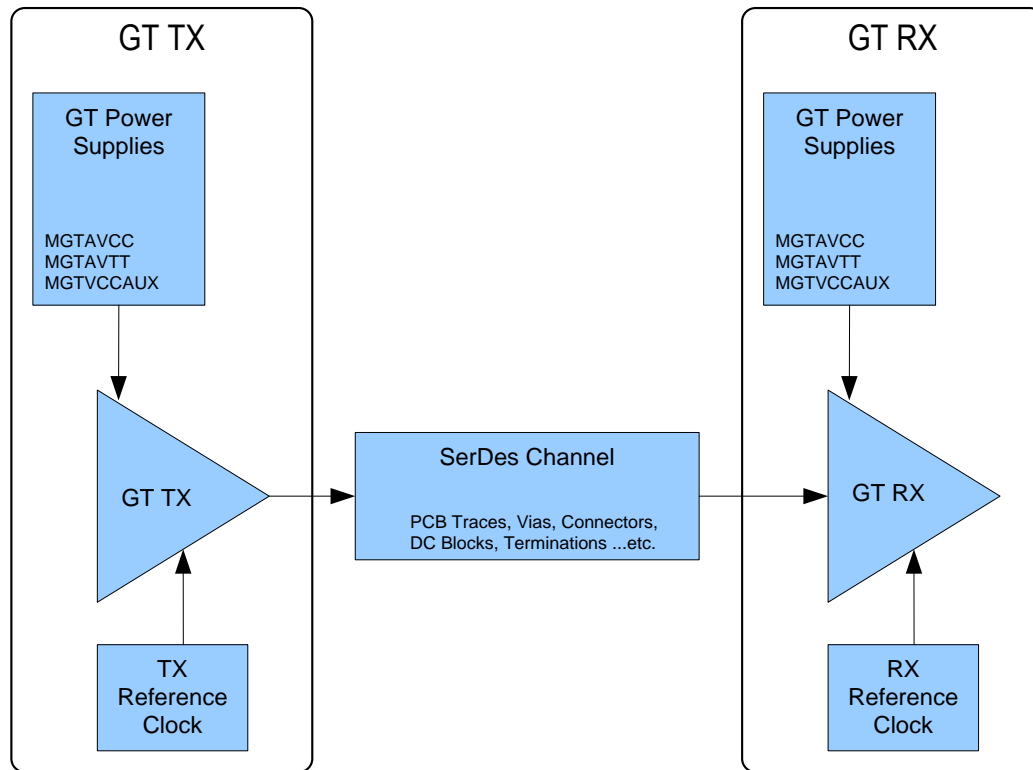
## – Transmitter

## – Receiver

## – Reference Clock

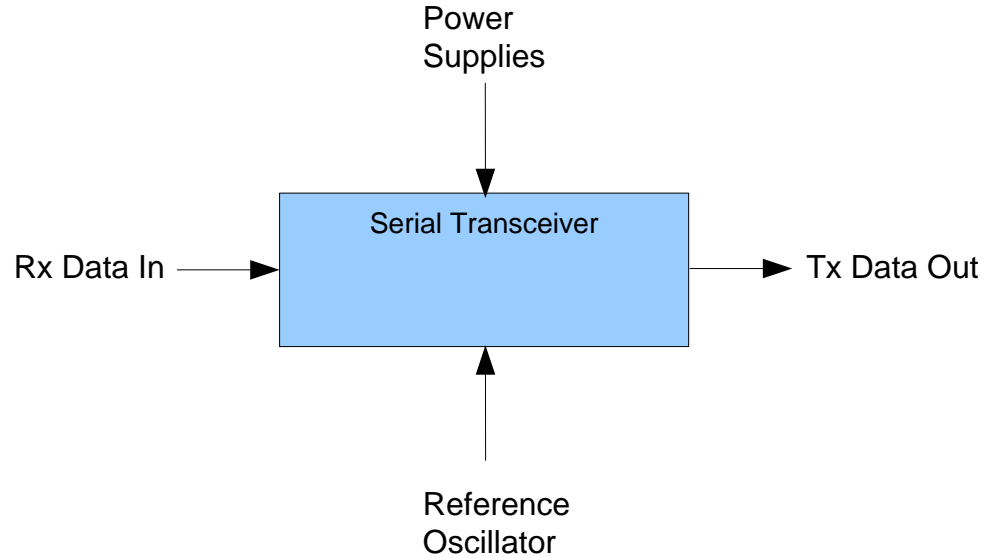
➤ Verify connectivity

➤ Verify compliance



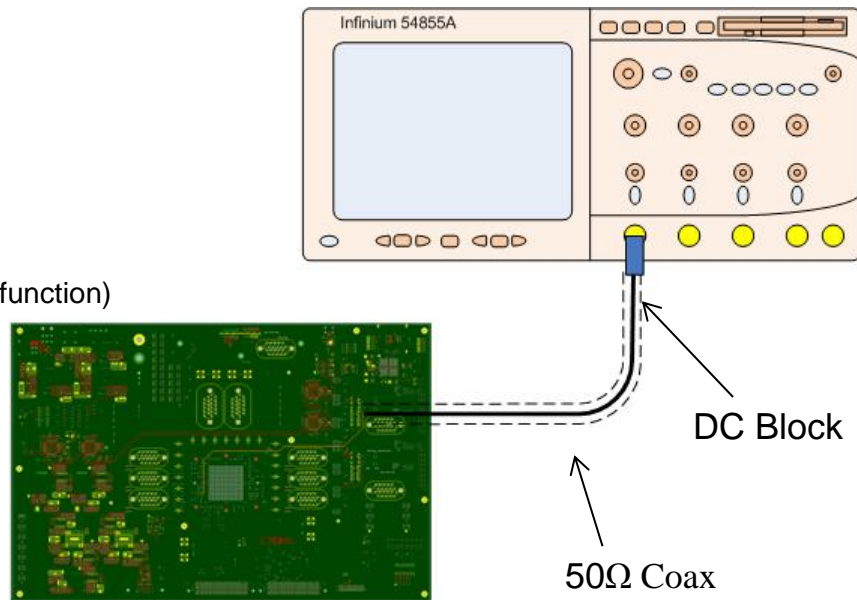
# SerDes Link Debug – 4 Port Device

- Power Supplies
  - MGTAVCC
  - MGTAVTT
  - MGTVCCAUX
- Transmitter
- Receiver
- Reference Clock



# SerDes Link Debug – Power Supply Measurements

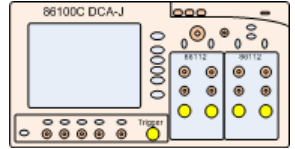
- Use 50 ohm probing. Using 50 ohms makes it easy to have a constant impedance for the entire path from the DUT to the oscilloscope input.
- Band limit the measurement. Limiting the bandwidth will
  - Reduce confusion from out-of-band energy.
  - Allows for easier detection and interpretation of measured waveform. (i.e. observe only what matters)
- To band limit, use a low-pass filter by using either
  - External low-pass filter between the DUT and scope input
  - Math processing function on the oscilloscope (Low-pass filter function)



# SerDes Link Debug – Clock Measurements

- Clock measurements

- Use TX output to measure clock frequency and phase quality
- Use alternating pattern of equal numbers of one's and zero's to generate 'square wave'.
  - Frequency dependent channel losses are mitigated with alternating high-low pattern.
  - Pattern dependent distortion is minimized

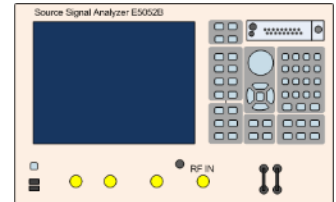


- Time Domain

- Use scope with Jitter analysis package to measure  $R_j$  from TX square wave pattern.
- Besides  $R_j$  look for  $P_j$ . Existence of  $P_j$  may be caused by interference (i.e. power supply noise, crosstalk, etc.)

- Frequency Domain

- Use Signal Analyzer or Spectrum Analyzer with phase noise package
- Measure phase noise
  - Observe noise up to PLL tracking frequency (~1 to 10MHz)
  - Look for significant spurs at higher frequencies.
  - Calculate  $R_j$  for sanity check (Most instruments will do this for you.)



# SerDes Link Debug – RefClk Phase Noise

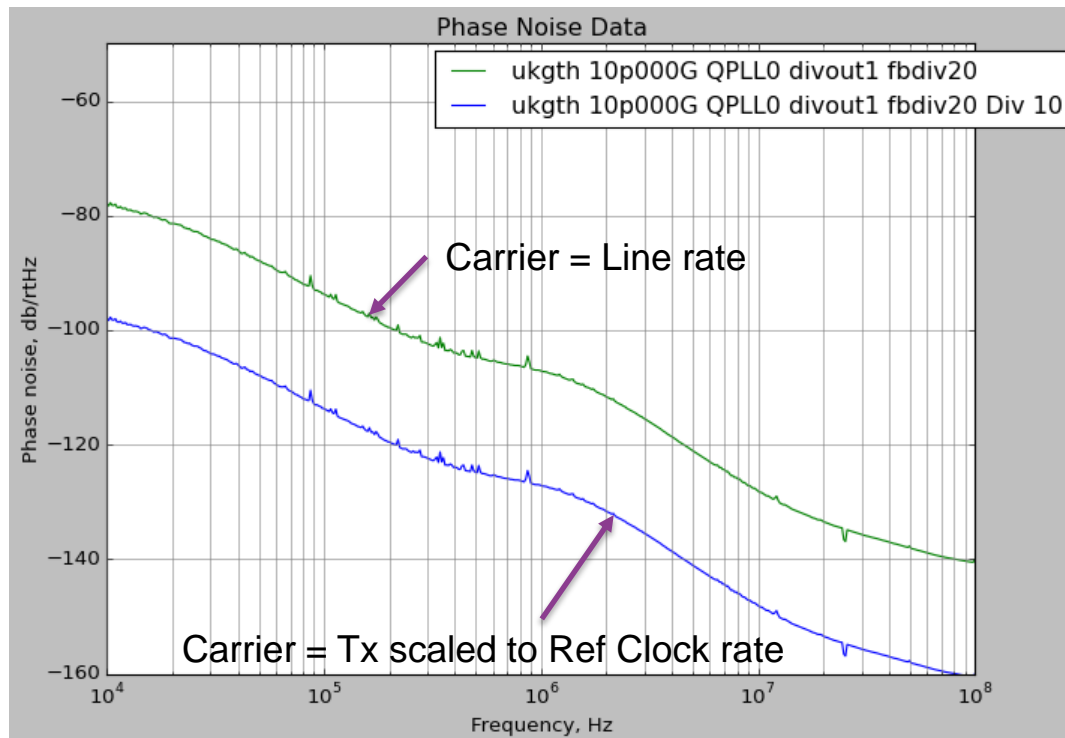
## UltraScale GTH

RefClk: 500.0 MHz

Line rate: 10.0 Gb/s

Scale phase noise to carrier  
Frequency:

$$\text{dB} + \left[ 20 \cdot \log_{10} \left[ \frac{F_{OUT}}{F_{IN}} \right] \right]$$



# SerDes Link Debug – RefClk Phase Noise

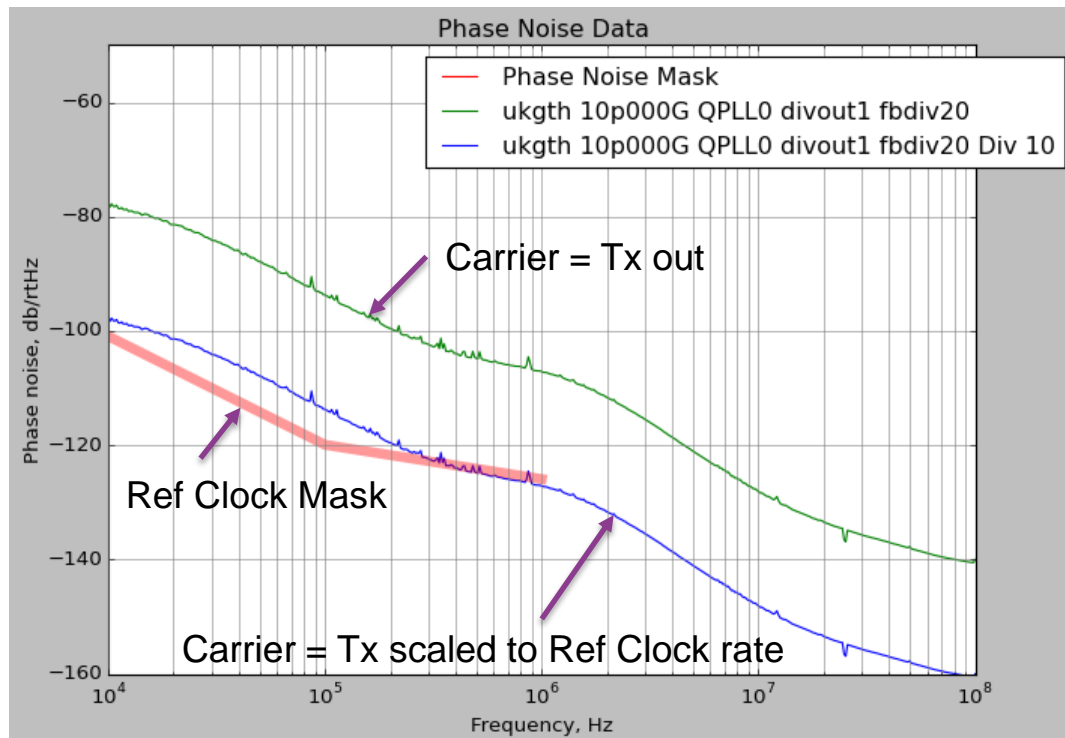
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# SerDes Link Debug – RefClk Phase Noise

## UltraScale GTH

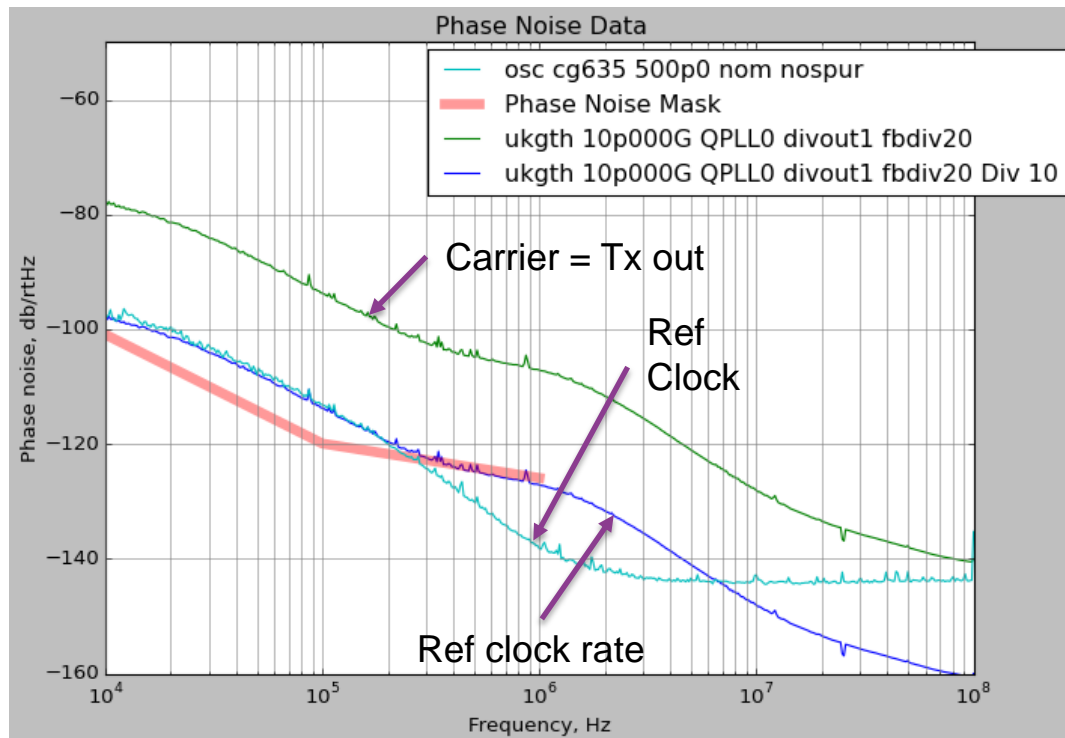
RefClk: 500.0 MHz

Line rate: 10.0 Gb/s

Scale phase noise to carrier

Frequency:

$$\text{dB} + \left[ 20 \cdot \log_{10} \left[ \frac{F_{OUT}}{F_{IN}} \right] \right]$$





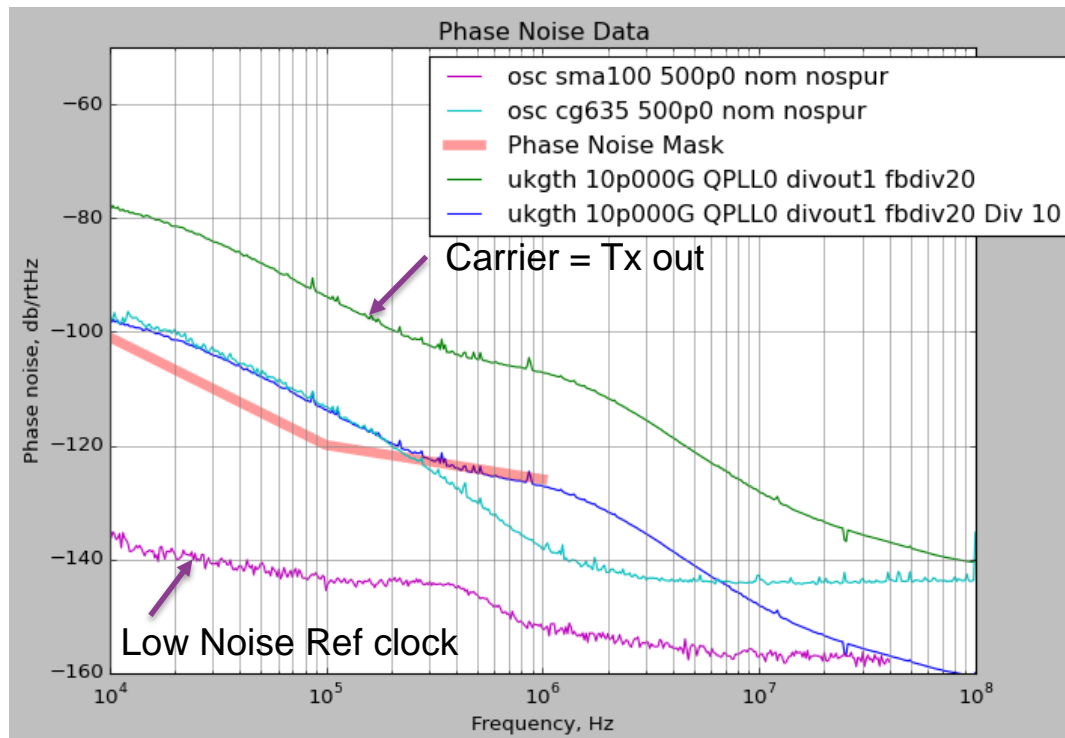
# SerDes Link Debug – RefClk Phase Noise

## UltraScale GTH

RefClk: 500.0 MHz  
Line rate: 10.0 Gb/s

Scale phase noise to carrier  
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# SerDes Link Debug – RefClk Phase Noise

## UltraScale GTH

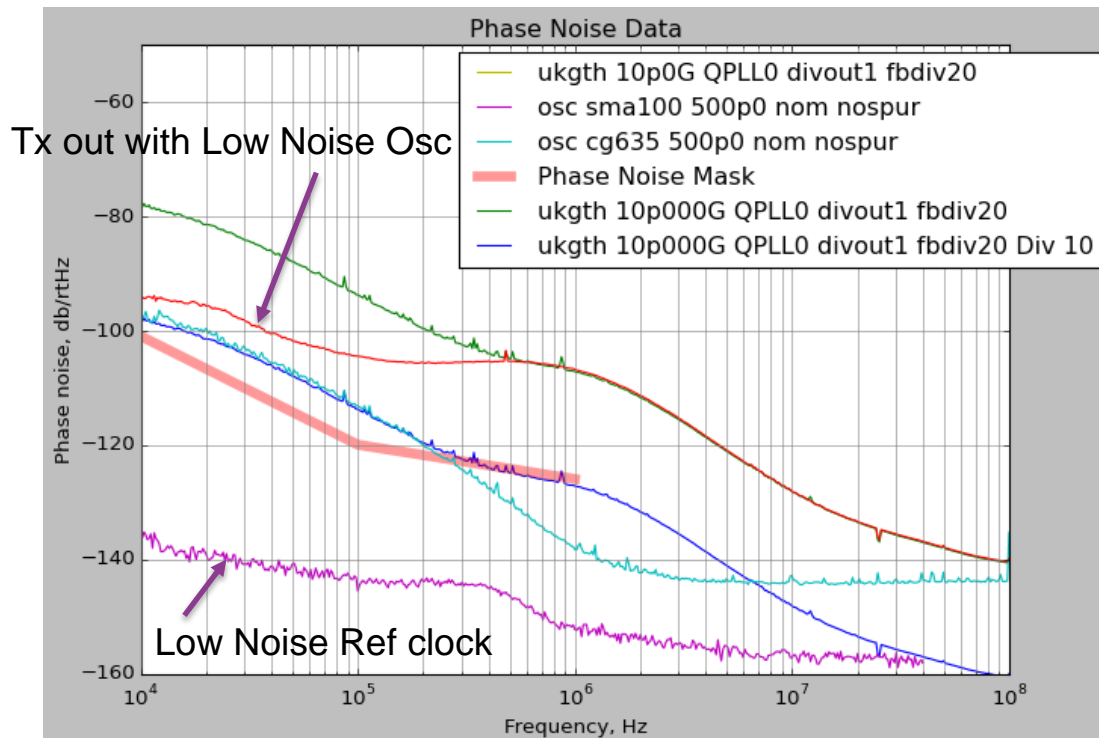
RefClk: 500.0 MHz

Line rate: 10.0 Gb/s

Scale phase noise to carrier

Frequency:

$$\text{dB} + \left[ 20 \cdot \log_{10} \left[ \frac{F_{OUT}}{F_{IN}} \right] \right]$$



# SerDes Link Debug – RefClk Phase Noise

## UltraScale GTH

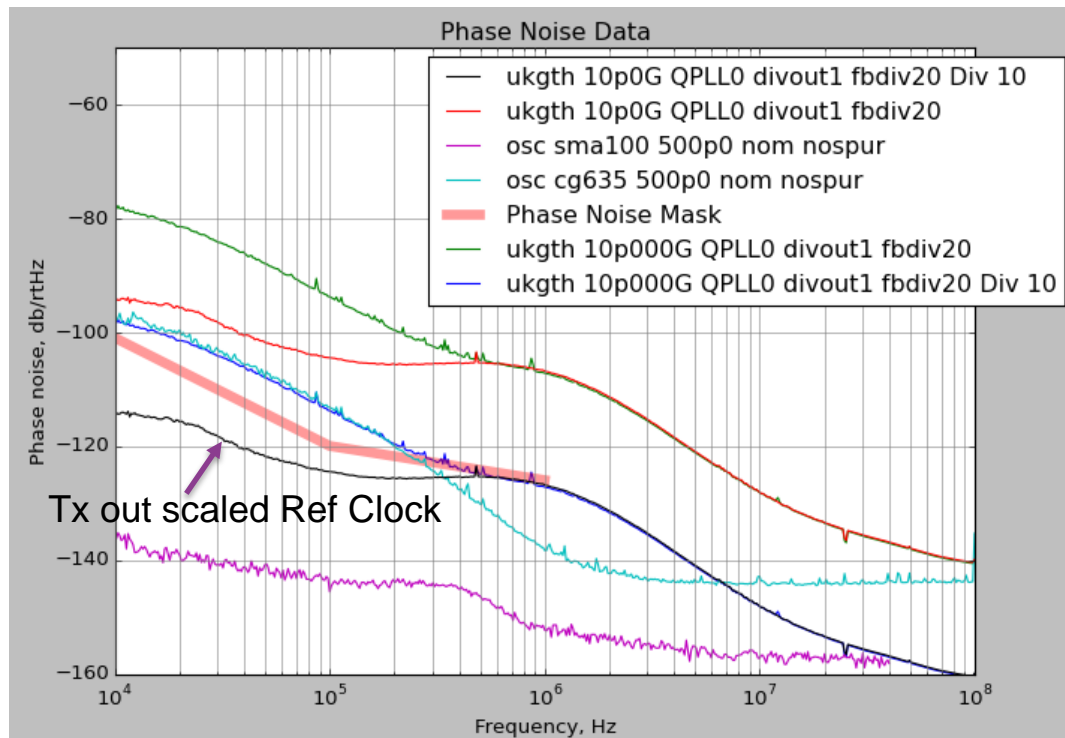
RefClk: 500.0 MHz

Line rate: 10.0 Gb/s

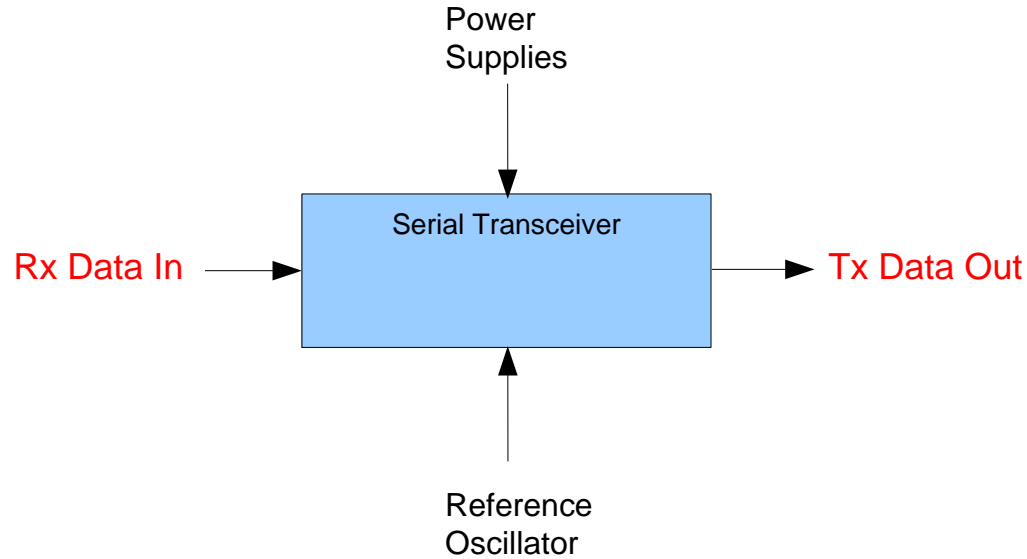
Scale phase noise to carrier

Frequency:

$$\text{dB} + \left[ 20 \cdot \log_{10} \left[ \frac{F_{OUT}}{F_{IN}} \right] \right]$$



# SerDes Debug – The Channel



...And now let's talk about  
The Channel

# AGENDA

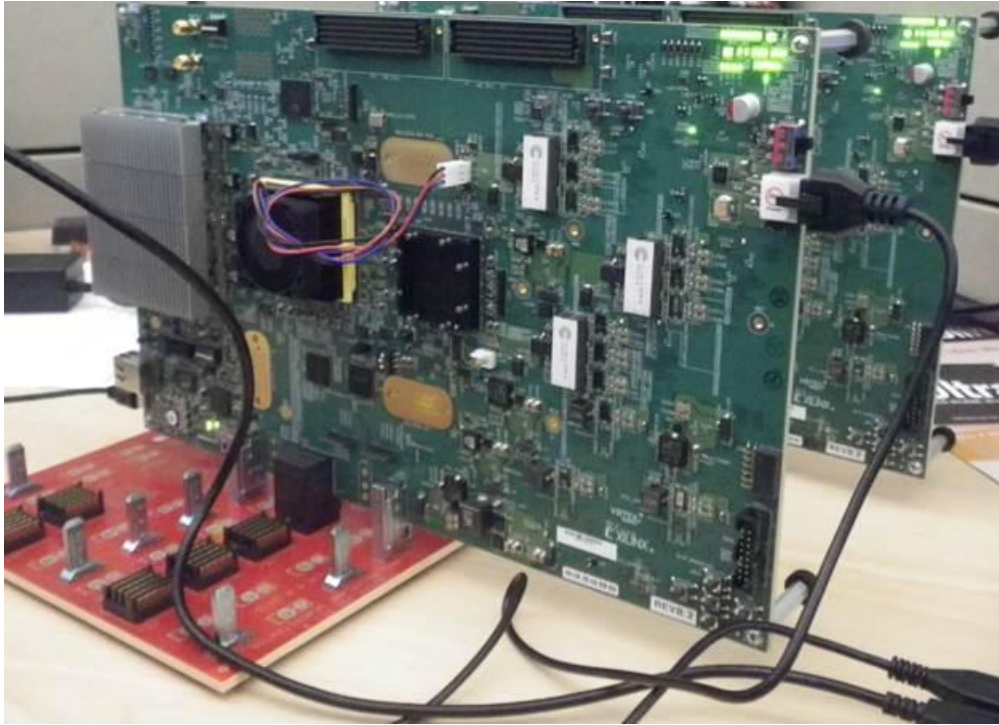


**Al Neves**

*Chief Technologist  
Wild River Technology*

- Test Strategies for SerDes Channels
- ➔ • **Forensic Channel Analysis**
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# Pathological Design Space – Advancing optimization and characterization



- Backplane characterization is a requirement
- Backplanes are, however, very complicated
- Difficult to form a coherent optimization strategy
- Difficult to establish clear margins versus issues
- *Good Engineering starts simple and systematic!*

**“It’s all about the  
margins...”**

**Jack Carrel**

# Pathological Design Space – Guiding Principles



- Replace backplane with **simple** pathological structures.
- Structures can be **systematically added**
- **Re-optimization** for new and simple channel, then...
- **Analysis of margin**

XTALK-32 Crosstalk Platform

ISI-32 Loss Platform

UltraScale+ TX and RX, 32Gbps NRZ



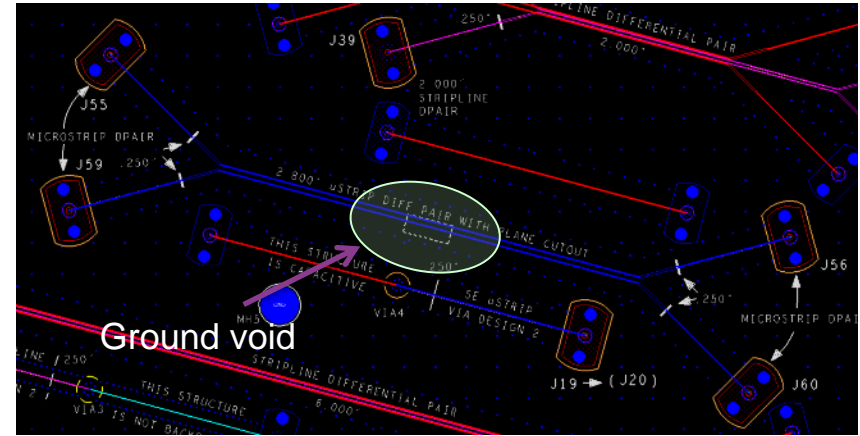
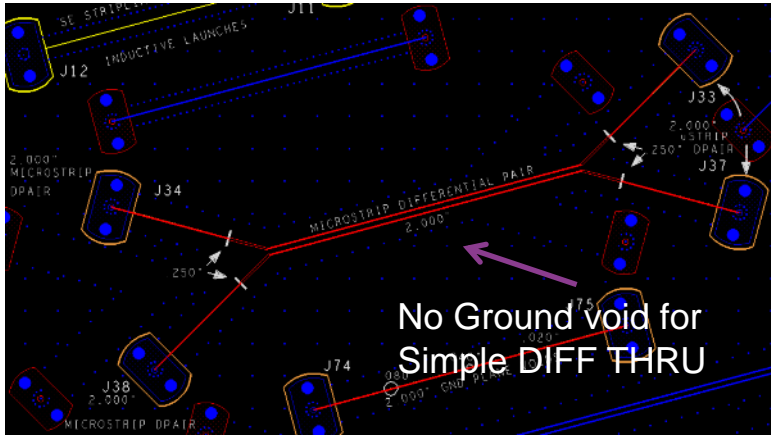
## Pathological is an Analogous Concept

- For our application it denotes a stellar signal integrity structure with something with intentional poor S.I. added
- The overall structure itself, aside from the pathological element, is healthy with good signal integrity

## Pathological Channel Concept – What is it?

- It is a family of interrelated structures
- There is always a root structure (like a THRU)
- Except for a single pathology, the structure is high S.I. (launches, transitions, fiber weave... etc.)

# Pathological Channel Concept – Example



- **2inch DIFF microstrip THRU**
- **Good signal integrity** and low loss
- *Also used for 2X THRU for AFR and Measure Based Modeled de-embedding structure on right*

- **2inch DIFF microstrip THRU Exact Copy of left + Asymmetric Ground Void**
- Results in **SDD11 degradation** and mode issue of **SCD21**

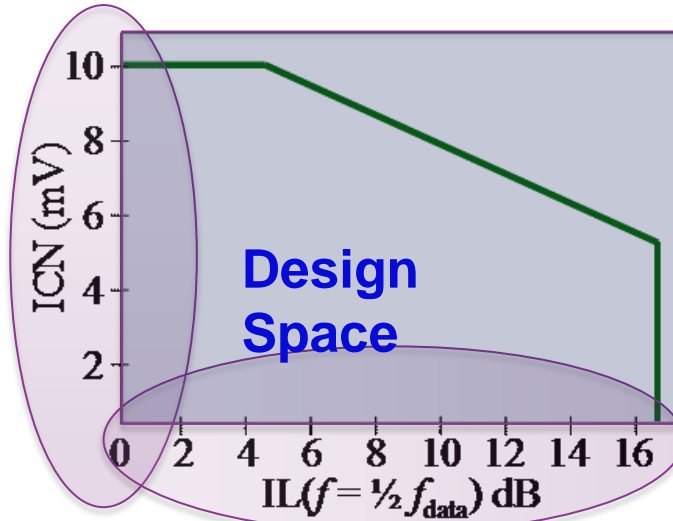
## Pathological Design Space - Benefits

- Improve SERDES characterization
- Ability to Improve manufacturing (Test, Product, and Characterization Engineering) and design process
- Drive technology tweaks and next generation products
- Provides systematic approach over complete design space of all pathologies
- Improve Measurement-Simulation correspondence
- Test IBIS AMI models over full Pathological space

# Pathological Design Space Concept – 2-D Space

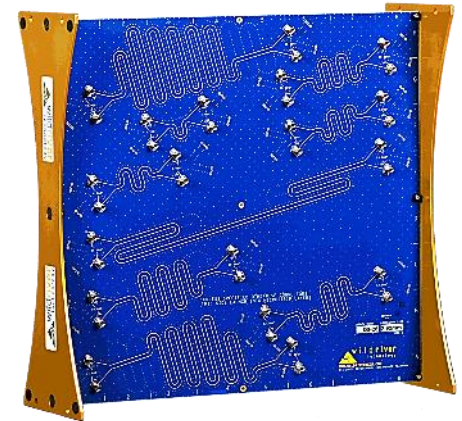


**Crosstalk Noise Test**  
vehicle, calculated RX noise  
as Integrated Crosstalk Noise  
(ICN)



**Insertion Loss Test**  
Vehicle (IL) at Nyquist  
Sampling Freq

Loss and Crosstalk combinations can be mapped over the entire **design space**



# Pathological Space – Loss Example

**START: Clean  
Pristine Low-Loss  
Channel**

**+Moderate Loss**

**+ RJ**

**+ SDD11  
Degradation**

**+ XTALK**

**+ Resonance**

**+More Loss**

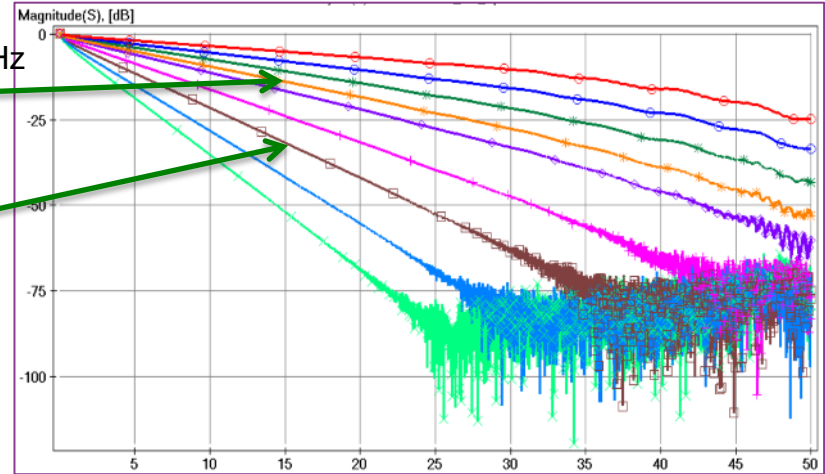
next patho

next patho

next patho

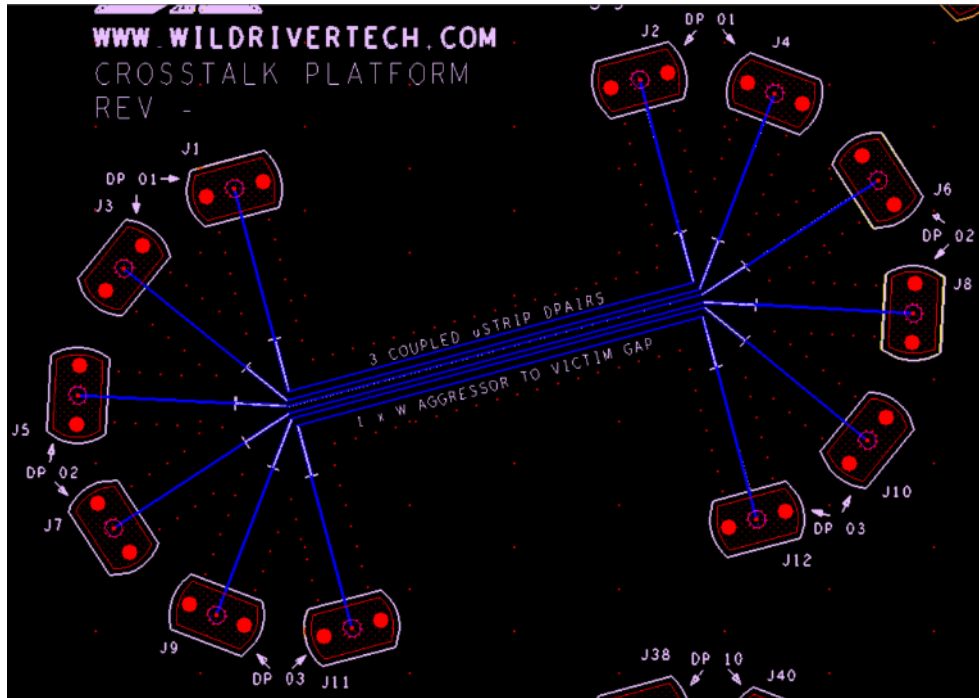
next patho

next patho



First start with pristine loss due to dielectric+skin of real channels, then add other pathologies

# Pathological Design Space – Advancing optimization

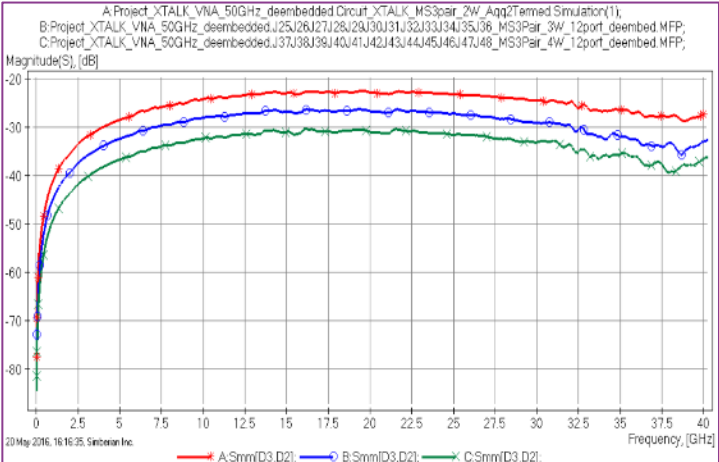


Crosstalk energy at RX also has SDD11 degradation, possible SCD21 (differential to common mode) and possible resonance.

So did the channel have issues due to RX noise due to crosstalk or the other issues?

This structure provides real crosstalk with good S.I.

# Pathological Crosstalk Example – Changing FEXT with same SDD11

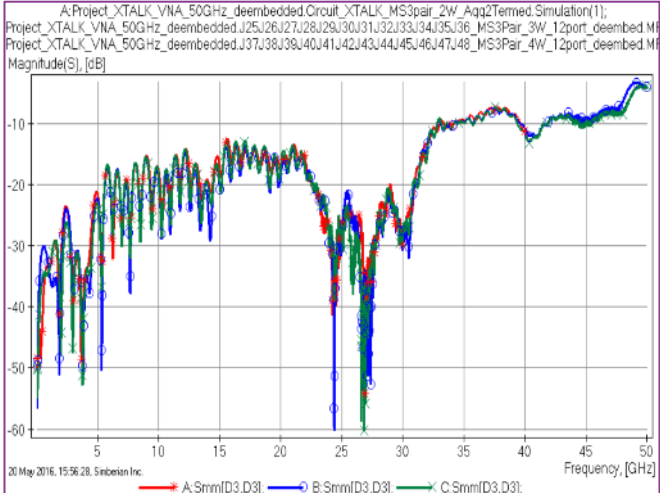
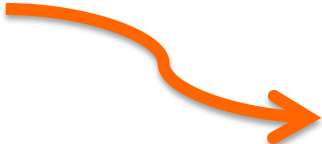


## Sdd[4,1] (FEXT)

Red = 2W Separation

Blue = 3W Separation

Green = 4W Separation



Each crosstalk structure is mapped to the same return loss, SDD11, only RX RMS noise changes



## In Summary.....

Establishing a Pathological approach uses high-signal integrity structures with isolated issues, and adds those structures in a systematic fashion to establish a channel which serves to improve the methodology of determining margin, and optimization strategies for the modern SERDES

# References

- DesignCon2015 Tutorial: Lee Ritchey, Heidi Banes, Chun-Ting “Tim” Wang Lee, Al Neves: **Breaking the 32 Gb/s Barrier: PCB Materials, Simulations, and Measurements**
- DesignCon2014 Presentation: Bob Buxton, Al Neves: **The Role of Improved Measurements and Tools in Assessing Simulation-Measurement Correspondence for 32 Gbps**
- DesignCon2011 Paper: James Bell, Scott McMorro, Martin Miller, Alfred Neves; **Developing Unified Methods of 3D Electromagnetic Extraction, System Level Channel Modeling, and Robust Jitter Decomposition in Crosstalk Stressed 10 Gbps Serial Data Systems**
- **WRT Skew Matched Data Sheets, [www.wildrivertech.com](http://www.wildrivertech.com)**
- **XTALK-28/32 Data Sheet**
- **ISI-28/32 Data Sheet**
- IEEE PG370 TG1, Test Fixture Group Draft 1.0

# AGENDA



**Heidi Barnes**

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Keysight Technologies*



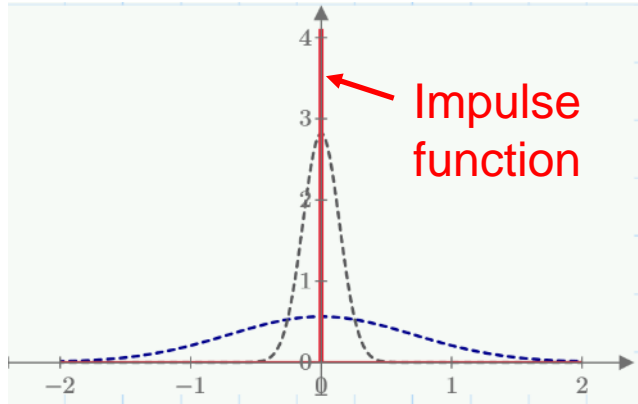
- Forensic Channel Analysis
- Test Strategies for Pathological Channels
- **Gaining Insight with the Pulse Response**

# The Well Known Impulse Response

Stimulus

Input:  $x(t)$

Dirac delta distribution\*



\*Dirac, Paul (1958), The Principles of Quantum Mechanics (4th ed.), Oxford at the Clarendon Press, ISBN 978-0-19-852011-5.

Linear Time-Invariant



Channel:  $h(t)$

$$y(t) = x(t) * h(t)$$

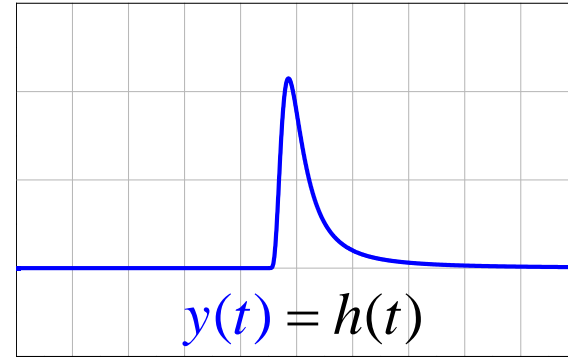
\*: Convolution operator

In an LTI system, the **impulse response** characterizes the system **completely**.

Response

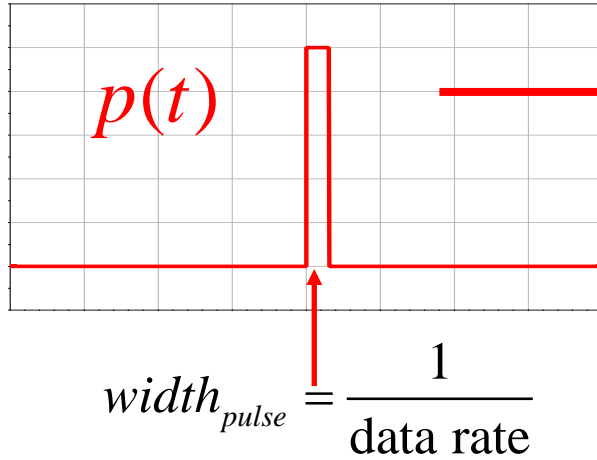
Output:  $y(t)$

Impulse Response of the channel



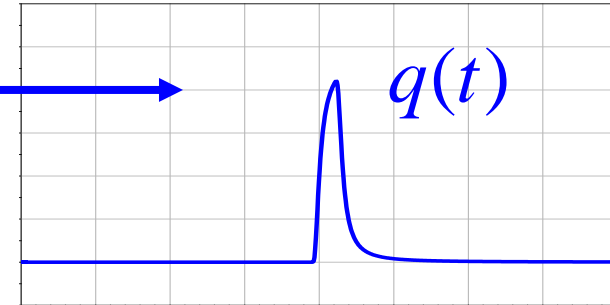
# And the Single Bit or Pulse Response

Single **pulse** function



Channel:  $h(t)$

Single **Pulse** Response

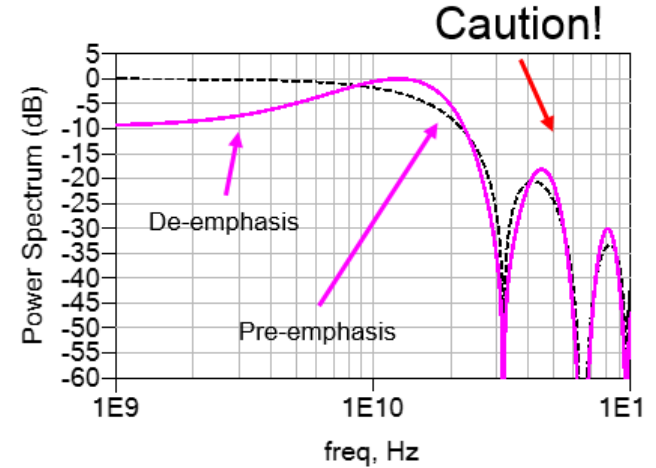
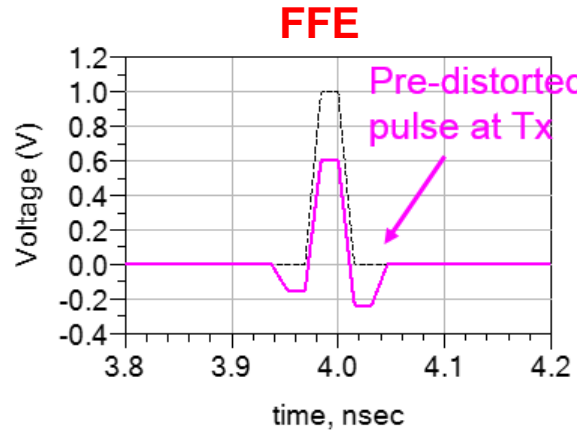
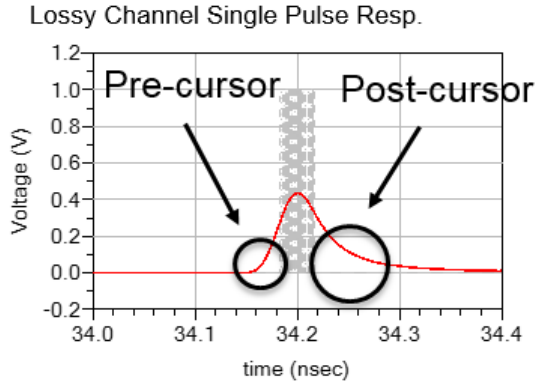


$$q(t) = p(t) * h(t)$$

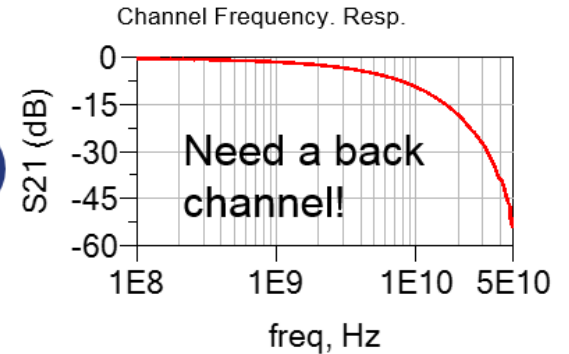
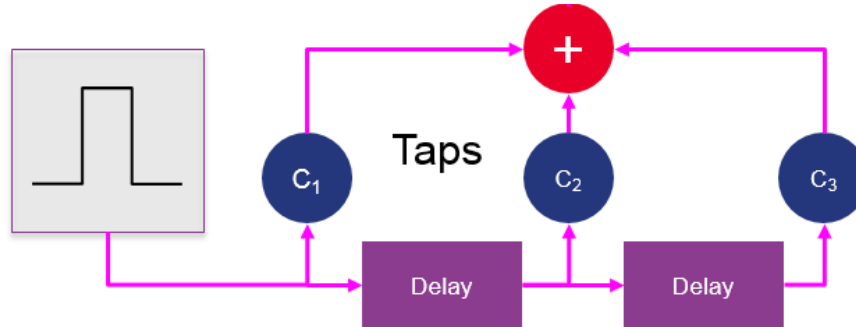
Single pulse response properties:

- Is a deconstructed eye.
- Shows effect of equalization.
- Gives insights to reflection and crosstalk.
- Helps characterize frequency-dependent loss .

# The Pulse Response Shows How the Feed Forward Equalizer Works

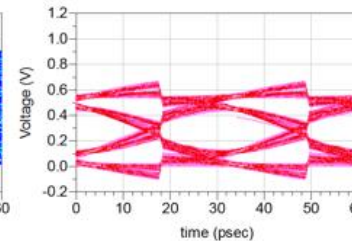
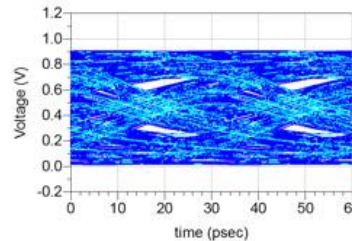
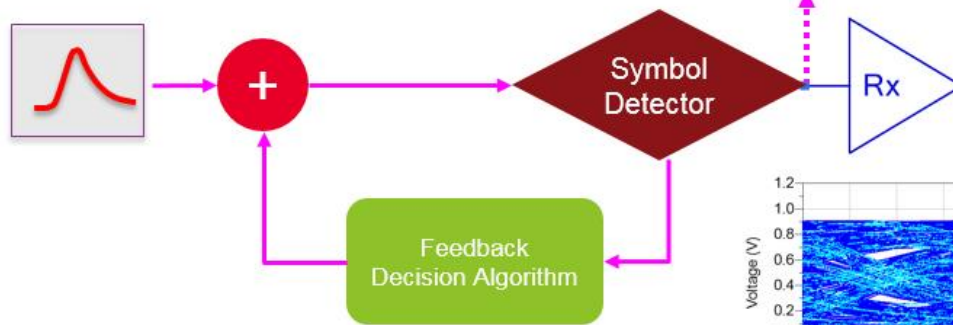
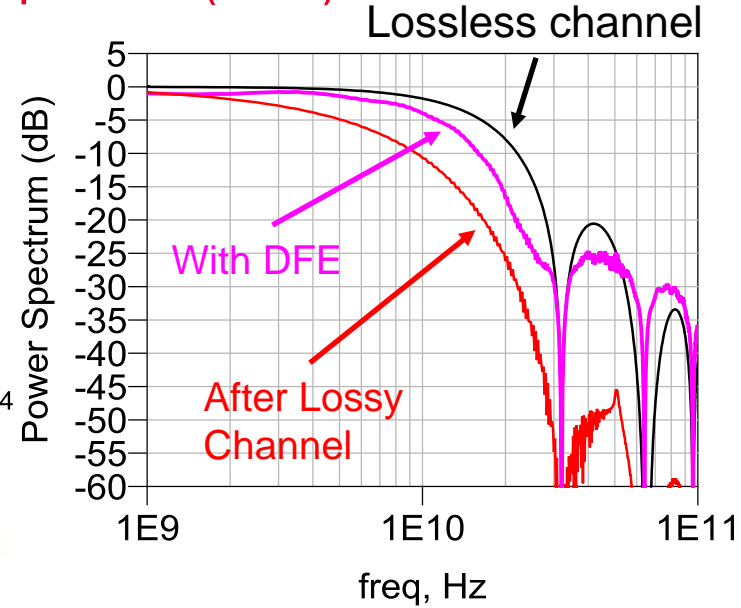
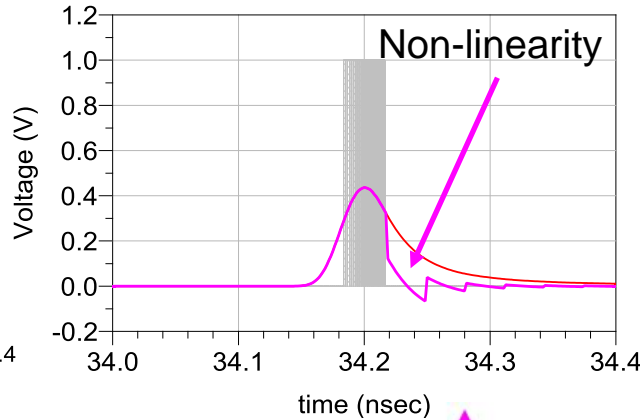
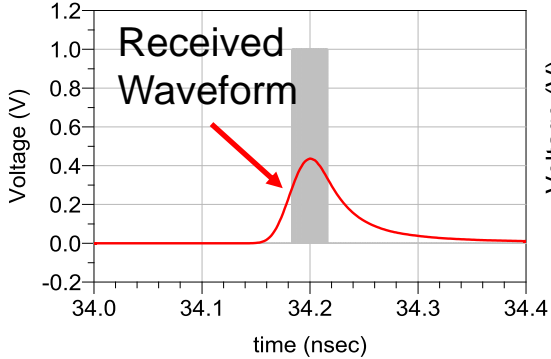


Feed Forward Equalizer Algorithm



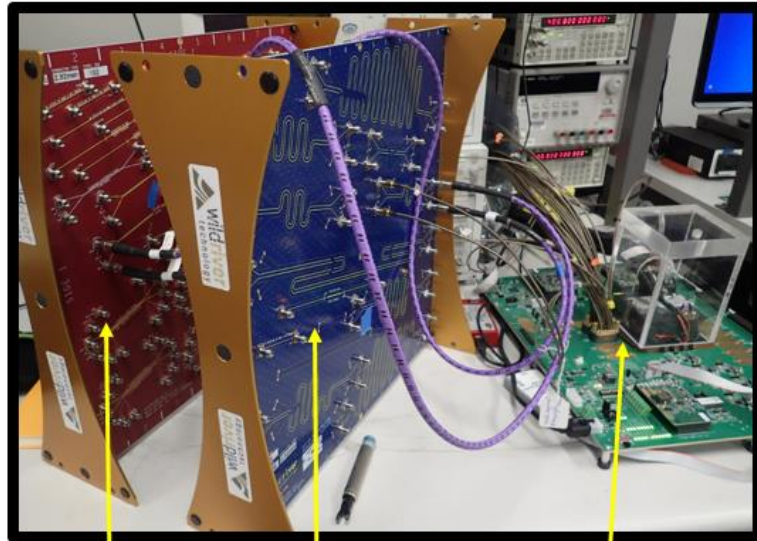
# Pulse Response of the Decision Feedback Equalizer (DFE)

Lossy Channel Single Pulse Resp.



# Measuring Band Limited S-Parameters

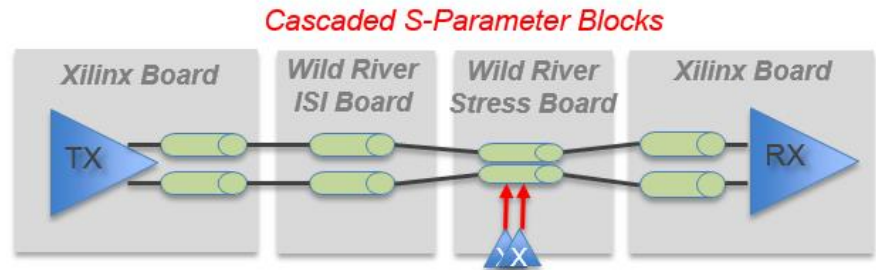
*Simulation requires a cascade of S-Parameters to analyze pathologies.*



**XTALK**

**ISI**

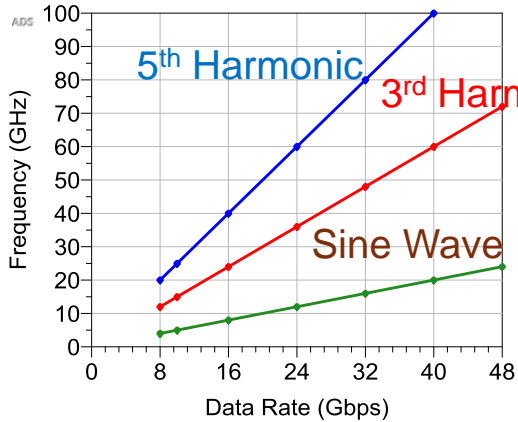
**Xilinx Board**





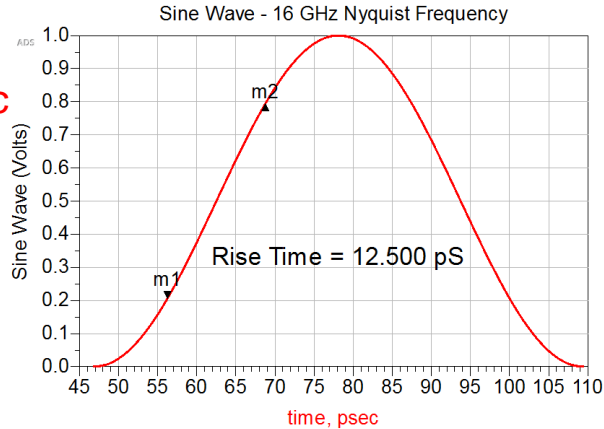
# Do the Rules of Thumb Really Help?

**Bandwidth Square Wave  
Harmonics**



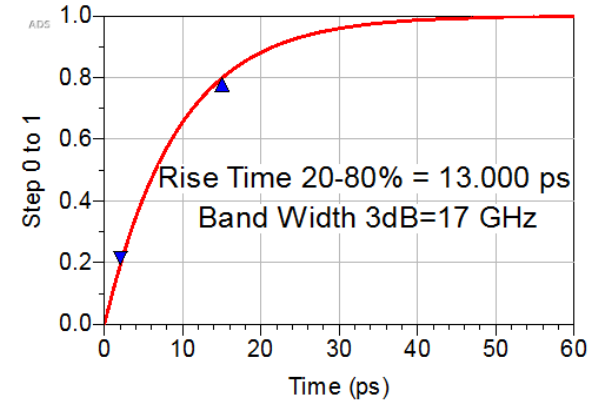
**Rise Time Sine Wave**

$$Frequency_{Nyquist} = \frac{0.2}{Rise\ Time_{(20\% \text{ to } 80\%)}}$$



**Bandwidth Step Response  
RC Tank Circuit**

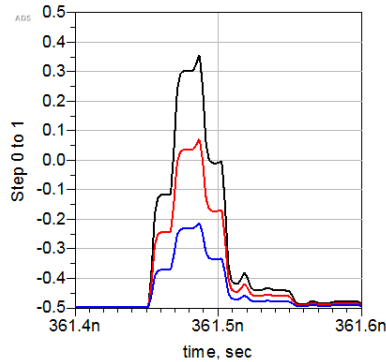
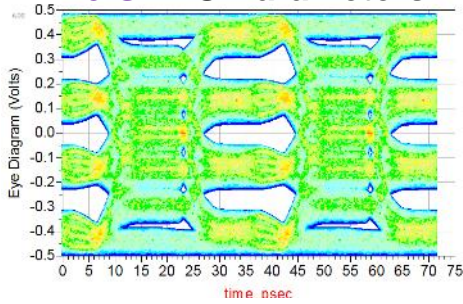
$$Frequency_{3dB} = \frac{0.22}{Rise\ Time_{(20\% \text{ to } 80\%)}}$$



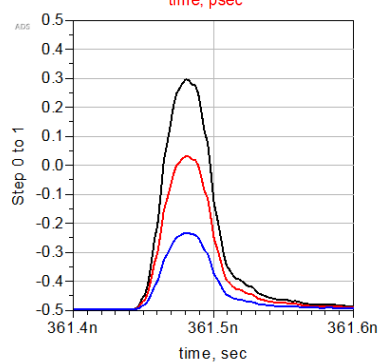
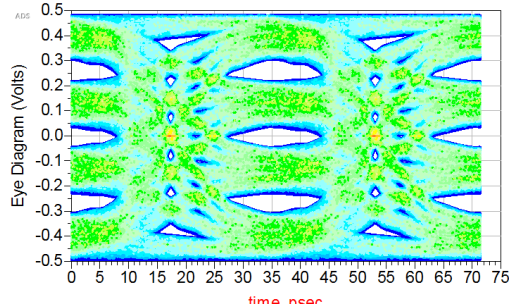
# Verify S-Parameter Bandwidth with Simulation

56GBaud PAM-4, 13pS Rise Time Tx, 4.5 in PCB ISI Channel, PRBS15

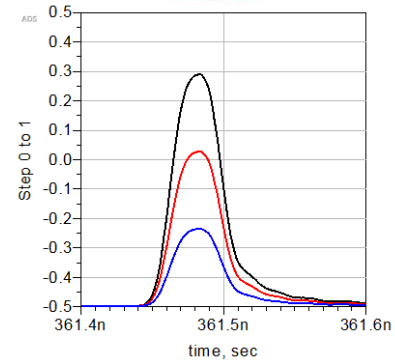
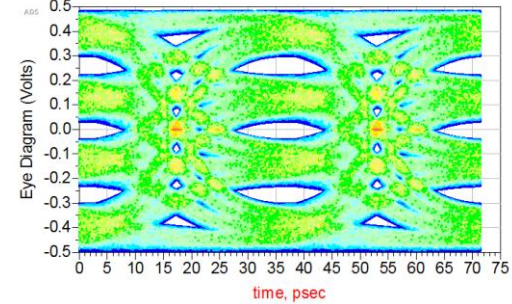
**Bandlimited**  
**16 GHz S-Parameters**



**Bandlimited**  
**32 GHz S-Parameters**



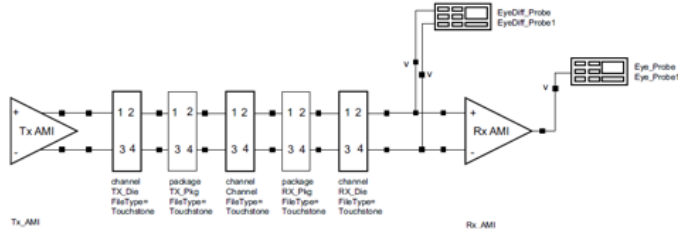
**Bandlimited**  
**48 GHz S-Parameters**



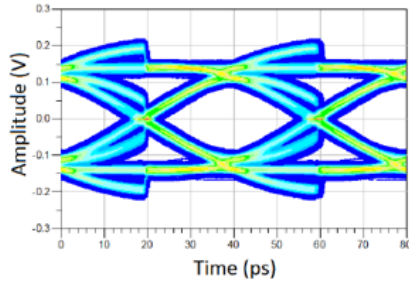
# Simulating the SERDES Channel with IBIS AMI Models

*Good IBIS AMI Models come with an example for comparison*

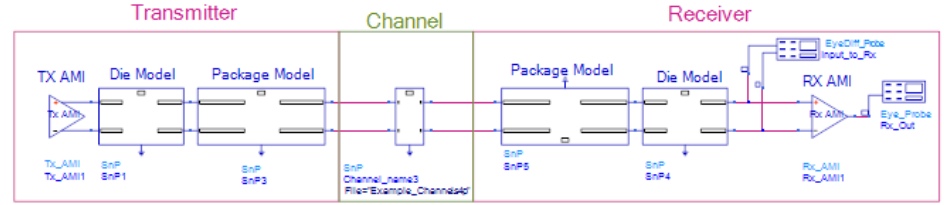
## IBIS AMI Kit Example



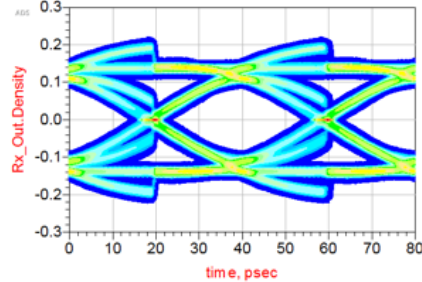
Equalized Eye Diagram



## My Simulator Setup



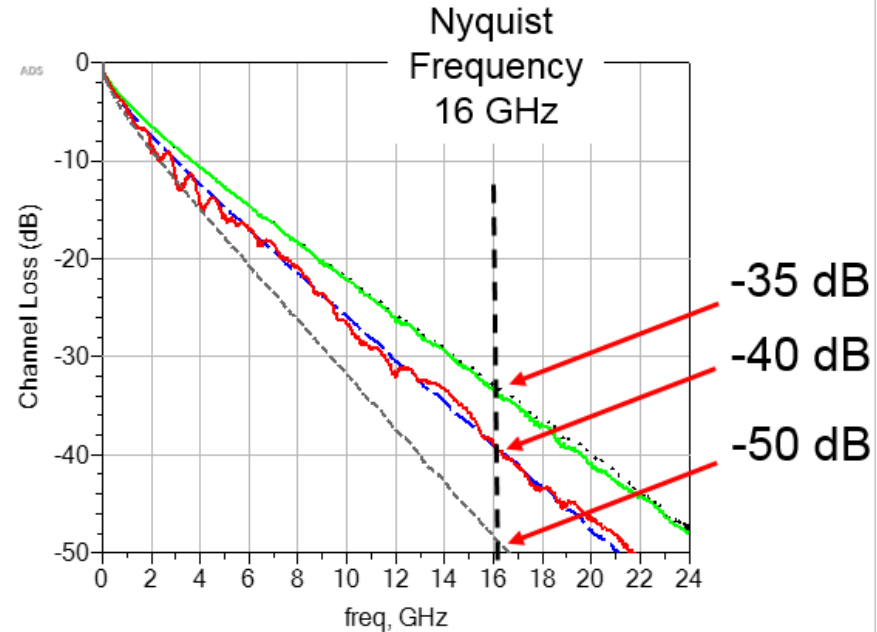
Equalized Eye Diagram



# All Loss is Not Created Equal

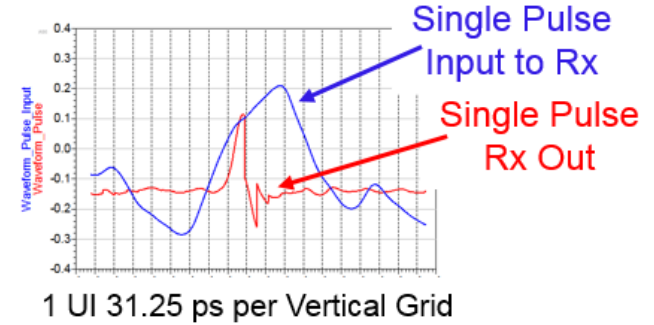
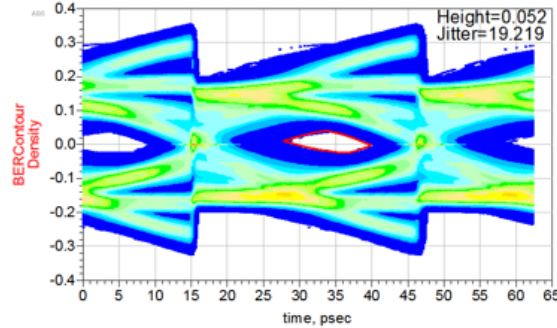
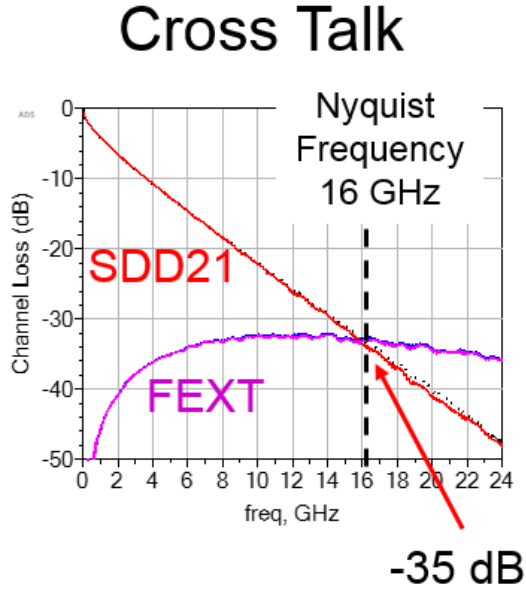
## Design of Experiments 3 Types of Signal Degradation

Total Loss	Material Loss	Reflections	XTALK
-35 dB	10in + 4.5in		3W Gap Aggressors
-40 dB	13in + 7.25 in	55 and 145 Return Loss	
-50 dB	15.5in + 13in		

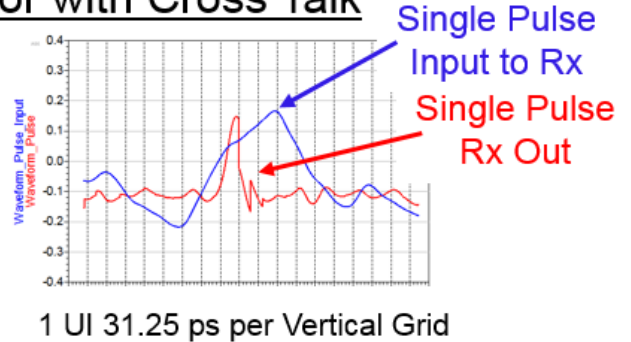
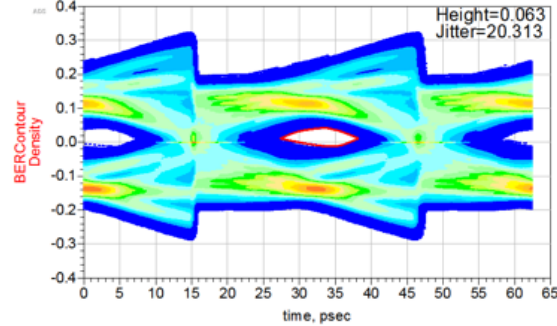


# Minimum Tx Equalization Maximizes Signal to Noise

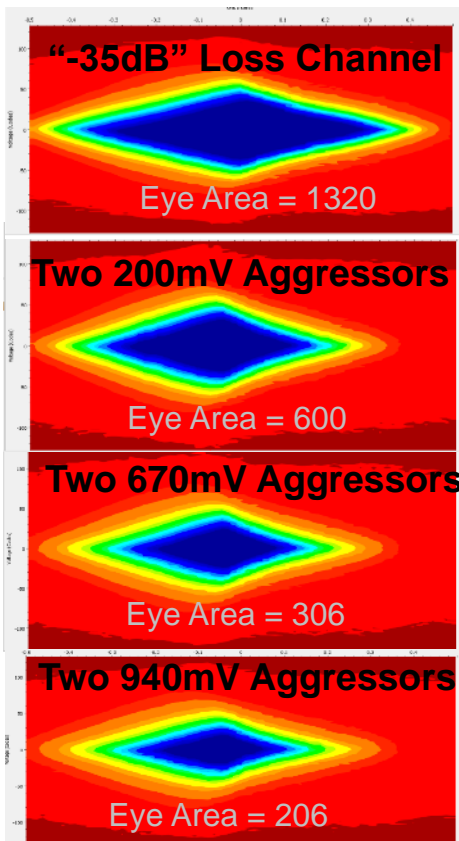
## 3 dB Tx Precursor with Cross Talk



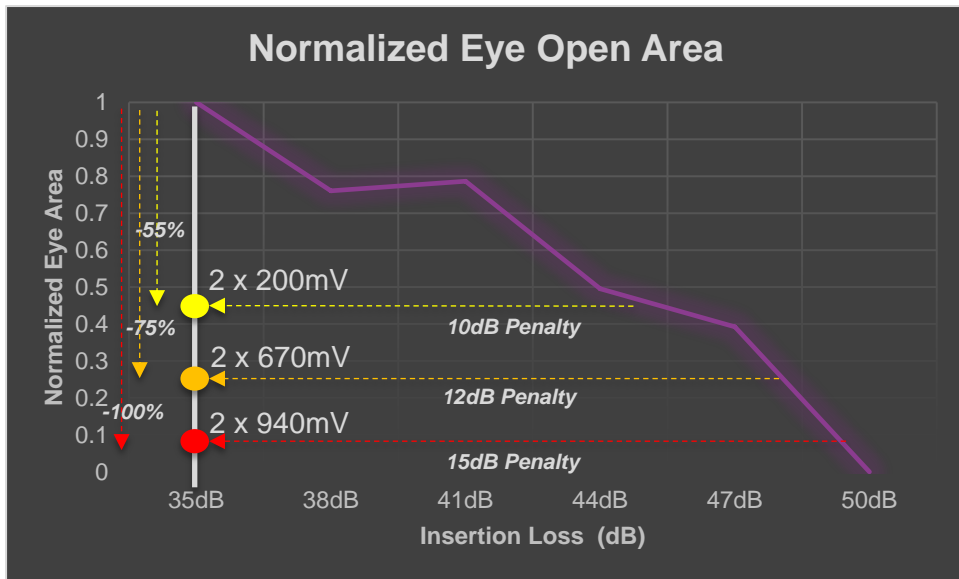
## 6 dB Tx Precursor with Cross Talk



# Measured Degradation by Cross Talk



32 Gbps, PRBS15, 3dB Tx Precursor, Auto Rx DFE



The Crosstalk also steals the margin for the insertion loss

## Summary

- The signal integrity of a channel must include analysis of all types of margin eating pathologies such as channel losses, clock noise, and power supply noise.
- A pathological approach breaks down the signal integrity of a SERDES channel to isolate sources of degradation for better optimization of design margins.
- The pulse response can be used to evaluate band-limited S-parameters and equalization techniques. This provides valuable insight for optimizing SerDes channels in the presence of crosstalk.

Thank You! .... And see us all at DesignCon next week!

**Tutorial Tuesday Jan. 31<sup>st</sup> 1:30 to 4:30pm**

**“32 to 56 Gbps Serial Link Analysis and Optimization Methods for Pathological Channels”**



***Request a Booth Demo***

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- DDR4 Power Aware Transient Simulation
- SERDES Compliance Test Benches
- Xilinx PAM4 Measurement and Simulation

**Wild River Technology Booth #850**

- Technology Development Platform 50GHz
- Check out our latest Hermetic Cables to 50GHz
- 70GHz Test Fixture Design
- CCIX Xilinx Demo





# Where to go next?



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